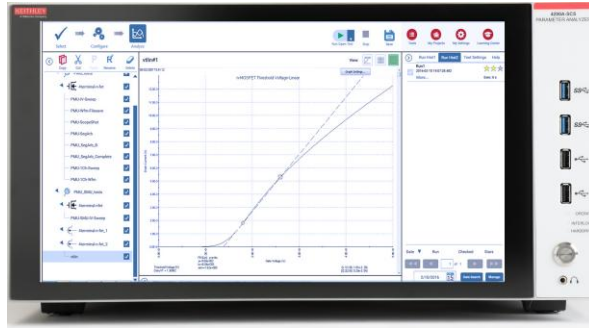


# 4200A-SCS Parameter Analyzer Fact Sheet

ACCELERATING INSIGHT, REDUCING COMPLEXITY



Research with speed and clarity



Quickly see your insights and discoveries come to life with the 4200A-SCS Parameter Analyzer

Features	Benefits
Modular, fully integrated parameter analyzer	Synchronized, wide range of electrical measurement and analysis capabilities to fully characterize semiconductor devices, materials and processes.
Clarius graphical user interface	Delivers fast characterization insight by reducing test set-up time, learning curve and results analysis
Built-in measurement expert videos	Get answers faster and investigate unexpected results quickly with measurement videos, on-demand webinars and application notes guidance.
Seamless switching between measurement types	Maintain the same impedance during your tests and reduce test time, measurement errors and complicated cabling.
Ready-to-use, modifiable application tests	You don't need to program complex measurements with over 450 tests to choose. Select from the library of devices, tests and projects to jump-start your research.
Upgradeability	Don't know what you'll be working on next year? Add additional instrument modules as your research requirements change – ensuring usefulness and return on your investment for years to come.

- **Industry's easiest** method to switch between measurement without re-cabling or lifting prober tips
- **Industry's first** instrument with YouTube-like built-in measurement videos from world-wide Application engineers to minimize learning curve and enable faster troubleshooting
- **50% reduction** in characterization complexity and test setup with over 450 tests, projects and devices
- **Add** instrumentation now – or later when measurement needs change
- **DC I-V, C-V and Pulsed I-V** measurements for complete characterization

# 4200A-SCS Parameter Analyzer Fact Sheet

## KEY SPECS AND ORDERING INFORMATION

Models	Range	Description
4200A-SCS	-	Parameter analyzer mainframe with display
4200A-SCS-ND	-	Parameter analyzer mainframe without display
4200-SMU	$\pm 100$ mA, $\pm 210$ V	Medium power SMU
4210-SMU	$\pm 1$ A, $\pm 210$ V	High Power SMU
4200-PA	0.1 fA resolution	Remote SMU Pre-amplifier Module
4210-CVU	1 kHz – 10 MHz $\pm 30$ V bias	Multi-frequency C-V Unit
4225-PMU	$\pm 40$ V, $\pm 10$ V, $\pm 800$ mA	Ultra-fast Pulsed I-V Unit
4220-PGU	$\pm 40$ V, $\pm 10$ V	Pulse Generator Unit
4225-RPM	100 nA	Remote Amplifier/Switch Module
4200A-CVIV	-	I-V, C-V Multi-Switch Module
4200A-SCS-PK1	$\pm 210$ V, $\pm 100$ mA, 0.1 fA resolution	High resolution I-V bundle
4200A-SCS-PK2	$\pm 210$ V, $\pm 100$ mA, 0.1 fA resolution 1 kHz – 10 MHz	High resolution I-V & C-V bundle
4200A-SCS-PK3	$\pm 210$ V, $\pm 1$ A, 0.1 fA resolution 1 kHz – 10 MHz	High power I-V & C-V bundle

Service Options	Description
<ul style="list-style-type: none"> <li>3Y-STD</li> <li>5Y-STD</li> </ul>	Standard calibration service 3 or 5 years
<ul style="list-style-type: none"> <li>3Y-17025</li> <li>5Y-17025</li> </ul>	ISO-17025 calibration service, 3 or 5 years
<ul style="list-style-type: none"> <li>EW</li> <li>3Y-EW</li> <li>5Y-EW</li> </ul>	KeithleyCare Gold Plan – extended warranty 1, 3 or 5 years
<ul style="list-style-type: none"> <li>C/TRACE-CHART</li> </ul>	Traceability chart
<ul style="list-style-type: none"> <li>C/NEW DATA ISO</li> </ul>	ISO-17025 calibration data for new units
<ul style="list-style-type: none"> <li>APPS SERVICE</li> </ul>	Customized applications assistance



Key Applications	Benefits
<ul style="list-style-type: none"> <li>Semiconductor device &amp; process characterization</li> </ul>	<ul style="list-style-type: none"> <li>Quickly <b>develop insight</b> into new device, material or process and rapidly understand operating performance.</li> </ul>
<ul style="list-style-type: none"> <li>Semiconductor Wafer-level Reliability</li> </ul>	<ul style="list-style-type: none"> <li>Perform WLR testing with confidence in order to transfer device from R&amp;D quickly while <b>ensuring reliability</b> standards</li> </ul>
<ul style="list-style-type: none"> <li>Semiconductor Failure Analysis</li> </ul>	<ul style="list-style-type: none"> <li>Quickly <b>determine root cause</b> of a failed device by reducing test complexity</li> </ul>
<ul style="list-style-type: none"> <li>Electrochemistry</li> </ul>	<ul style="list-style-type: none"> <li><b>Stay focused</b> and gain insight into performance of samples, materials or species</li> </ul>